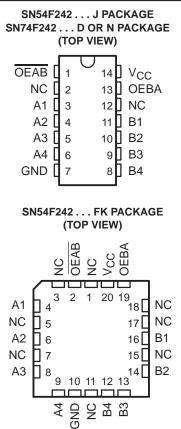
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- Asynchronous Communication Between **Data Buses**
- Local Bus-Latch Capability
- Inverting Logic
- **Package Options Include Plastic** Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

#### description

These quadruple bus transceivers are designed for asynchronous communications between data buses. The control function implementation allows for maximum flexibility in timing. These devices allow data transmission from the A bus to the B bus or from the B bus to the A bus depending upon the logic levels at the output-enable (OEBA and OEAB) inputs. The output-enable inputs can be used to disable the device so that the buses are effectively isolated.

configuration The dual-enable gives the quadruple bus transceivers the capability to store data by simultaneous enabling of OEBA and OEAB. Each output reinforces its input in this transceiver configuration. Thus, when both control inputs are enabled and all other data sources to the two sets of bus lines are at high impedance, both sets of bus lines (eight in all) remain at their states. The 4-bit codes appearing on the two sets of buses will be complementary for the 'F242.



NC - No internal connection

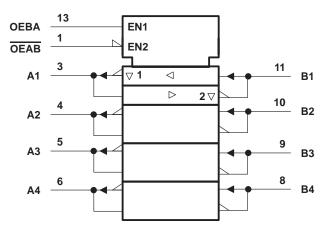
The SN54F242 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74F242 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE								
INP	UTS	FUNCTION						
OEAB	OEBA	FUNCTION						
L	L	A to B						
н	Н	B to A						
н	L	Isolation						
L	Н	Latch A and B (A = B)						

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

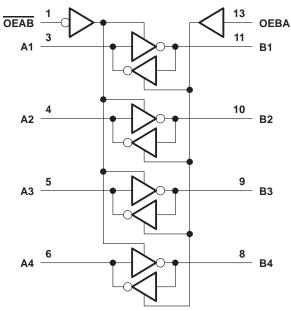
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### logic symbol<sup>†</sup>



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.



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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub> Input voltage range, V <sub>I</sub> (see Note 1) Input current range	-1.2 V to 7 V
Voltage range applied to any output in the disabled or po	ower-off state $\dots \dots \dots$
Voltage range applied to any output in the high state .	-0.5 V to V <sub>CC</sub>
Current into any output in the low state: SN54F242	
SN74F242	
Operating free-air temperature range: SN54F242	–55°C to 125°C
SN74F242	0°C to 70°C
Storage temperature range	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.

#### recommended operating conditions

		SN54F242			SN74F242			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
$V_{IL}$	Low-level input voltage			0.8			0.8	V
IIK	Input clamp current			-18			-18	mA
IOH	High-level output current			- 12			- 15	mA
IOL	Low-level output current	48				64	mA	
TA	Operating free-air temperature	-55		125	0		70	°C



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#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		S	SN54F242			SN74F242		
				MIN	түр†	MAX	MIN	TYP†	MAX	UNIT
VIK		V <sub>CC</sub> = 4.5 V,	lı = –18 mA			-1.2			-1.2	V
			I <sub>OH</sub> = - 3 mA	2.4	3.3		2.4	3.3		v
V		V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = - 12 mA	2	3.2					
∨он			I <sub>OH</sub> = - 15 mA				2	3.1		
		V <sub>CC</sub> = 4.75 V,	IOH = - 3 mA				2.7			
			I <sub>OL</sub> = 48 mA		0.38	0.55				v
VOL		$V_{CC} = 4.5 V$	I <sub>OL</sub> = 64 mA					0.42	0.55	
	A or B port	V <sub>CC</sub> = 5.5 V	VI = 5.5 V			1			1	A
łı	Control inputs		V <sub>I</sub> = 7 V			0.1			0.1	mA
	A or B port‡	V <sub>CC</sub> = 5.5 V,				70			70	
IН	Control inputs		V <sub>1</sub> = 2.7 V			20			20	μA
I <sub>IL</sub> ‡		V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.5 V			- 1			- 1	mA
los§		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0	-100		-225	-100		-225	mA
ICC			Outputs high		30	46		30	46	
		$V_{CC} = 5.5 V,$ See Note 2	Outputs low		46	69		46	69	mA
			Outputs disabled		42	63		42	63	

<sup>†</sup> All typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25^{\circ}C$ .

 $\ddagger$  For I/O ports, the parameters  $I_{IH}$  and  $I_{IL}$  include the off-state output current.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: ICC is measured either with all transceivers enabled in only one direction or all transceivers disabled.

### switching characteristics (see Note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 5 V,$ $C_L = 50 pF,$ $R_L = 500 Ω,$ $T_A = 25°C$			$V_{CC} = 4.5 V \text{ to } 5.5 V,$ $C_L = 50 \text{ pF},$ $R_L = 500 \Omega,$ $T_A = \text{MIN to MAX}$ SN54F242 SN74F242				UNIT
			MIN	<sup>′</sup> F242 TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	A or B	B or A	2.2	4.1	6.5	2.2	9	2.2	7.5	ns
<sup>t</sup> PHL			1	2.6	4.5	0.5	5	1	4.5	
tPZL	Enable	A or B	2.7	5.6	7.5	2.2	10	2.7	8.5	ns
<sup>t</sup> PZH			2.7	6.1	9	2.2	12	2.7	10.5	
<sup>t</sup> PHZ	Disable	A or B	1.8	6.6	9	1.8	11	1.8	9.5	ns
<sup>t</sup> PLZ		AUB	2.7	5.6	9.5	2.3	13.5	2.7	11	115

¶ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 3: Load circuits and waveforms are shown in Section 1.



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